

List of Exhibition at NC-AFM 2010
in Kanazawa, Japan, July 31 - Aug. 5, 2010

Offer No	Company	Contact	e-mail	Address	Tel/Fax	URL	Contents of Exhibition
1	SPECS Surface Nano Analysis GmbH		support@specs.com sales@specs.com	Voltastrasse 5 13355 Berlin, Germany	+49 (0)30 46 78 24 0 /+49 (0)30 46 42 083	http://www.specs.de	Systems and Components for Surface Analysis/Scanning Probe Microscopy Nanonis SPM Control System /Nanonis OC4 Station KolibriSensor
2	Tec Corporation	Keigo MATSUDA	matsuda@t-e-c.co.jp	7-19-26-311 Oizumigakuencho, Nerima-ku, Tokyo 178-0061, Japan	+81(0)3-5935-1060 /+81(0)3-5935-1070	http://www.kagaku.com/tec/	
3	ROCKGATE CORPORATION	Shoko SAKAKIBARA	sakakibara@rockgateco.com	1-11-12, Hongo, Bunkyo-ku, Tokyo 113-0033, Japan	+81(0)3 5805 8411 /+81(0)3 5805 8431	http://www.rockgateco.com	Nano positioners and posters of SPM
	attocube systems		info@attocube.com	Königinstrasse 11a RGB 80539 München, Germany	+49(0)89-2877809-0 /+49(0)89-2877809-19	http://www.attocube.com	
4	Omicron Nanotechnology			Limburger Str. 75 65232 Taunusstein, Germany	+49-6128 987-0 /+49-6128 987-185	http://www.omicron.de/index.html	Demonstration of SoftWare Poster/catalog
	Omicron Nanotechnology Japan	Naoko OIWA	n.oiwa@omicron.jp	5-30-15, Kamata, Ota-ku, Tokyo 144-0052, Japan	+81(0)3-6661-0850 /+81(0)3-6661-0855	http://www.omicron.jp/website/	
5	Unisoku Co., LTD.	Toshiaki NAGAMURA	toshiaki@unisoku.co.jp	2-4-3 Kasugano, Hirakata, Osaka 573-0131, Japan	+81(0)72-858-6456 /+81(0)72-859-5655	http://www.unisoku.com/	UHV Scanning Probe Microscope
6	RHK Technology, Inc.	Sue FORST	info@rhk-tech.com	1050 East Maple Road Troy, Michigan 48063, USA	+1-248-577-5426 /+1-248-577-5433	http://www.rhk-tech.com/	UHV AFM / STM Surface Science Solutions featuring the Beetle™, Pan-Style, and QuadraProbe™ scan head architectures along with the R9 SPM Control System
7	JPK Instruments AG	Nobuhiro SAITO	saitoh@jpk.com	Bouchéstrasse 12 Haus 2, Aufgang C 12435 Berlin, Germany Ariake Frontier Build. B-9 3-7-26 Ariake, Goutou, Tokyo 135-0063, Japan	+49-30-5331-12070 /+49-30-5331-22555 +81-3-550-9364 /+81-3-5530-9230	http://www.jpk.com	Atomic Force Microscopy NanoWizardII Automated Force Spectroscopy Robot 30
8	TOYO Corporation	Masatoshi EGAWA	egawam@toyo.co.jp	1-6, Yaesu 1-chome, Chuo-ku, Tokyo 103-8284, Japan	+81-3-3279-0771 /+81-3-5205-2030	http://www.toyo.co.jp/spm	Scanning Probe Microscope AFM Probe
9	Park Systems	Yoshikazu MIYASHITA	miyashita-yoshikazu@parkAFM.co.jp	Park Systems Japan Inc. NK Dai-ichi Bldg. 1F, 1-17-1 Kanda-Nishikicho, Chiyoda-ku, Tokyo 101-0054, Japan	+81-3-3219-1001 /+81-3-3219-1002	http://parkafm.com/jp/	NC-AFM Technology
10	Advanced Algorithm & Systems Co., Ltd.	Yoshie MORITA	y-morita@aaS-ri.co.jp	Ebisu IS bldg. 7F, Ebisu 1-13-6, Shibuya, Tokyo 150-0013, Japan	+81-3-3447-5501 /+81-3-3447-4100	http://www.aas-ri.co.jp/	Advanced simulator for the Scanning Probe Microscopy
11	SHIMADZU CORPORATION	General Planning Unit				http://www.shimadzu.co.jp/surface/products/sol/sp_index.html	Scanning Probe Microscope SPM-9600 and applications
12		Marketing Department	surface2@group.shimadzu.co.jp	1 Nishinokyo-Kuwabaracho, Nakagyo-ku, Kyoto 604-8511, Japan	+81-75-823-1468 /+81-75-841-9325	http://www.shimadzu.com/products/lab/surface/spmd.html	Prototype of FM-AFM in air/liquid
13	Zurich Instruments	Stephan KOCH (Marketing & Sales) Sadik HAFIZOVIC (at the exhibition)	info@zhinst.com	Technoparkstrasse 1 CH-8005 Zurich Switzerland	+41-44-5150410 /+41-44-5150419	http://www.zhinst.com	Dual-channel 50 MHz PLL for AFM Dual-input channel, high-performance 50 MHz lock-in amplifier Multi-frequency measurements Live demonstration of PLL and lock-in performance
14	NanoMagnetics Instruments Ltd.	Ahmet Oral	info@nanomagnetics-inst.com	Suite 290 266 Banbury Road Oxford OX2 7DL, United Kingdom	+44 7906 159 508 /+44 870 7620573	http://www.nanomagnetics-inst.com	Aqua nc-AFM in Liquids/Air operating at Atomic resolution & ncAFM Control Electronics Posters of : USB Digital PLL Low Temperature AFM
15	IOP Publishing	Masaaki Osanai	custserv@iop.org	9th Floor Buyo Bldg. 3-8-16 Nihonbashi Chuo-ku, Tokyo 103-0027 JAPAN	+44 7906 159 508 /+44 870 7620573	http://www.iop.org/	Peer Reviewed Journals related to NC-AFM. Sample copies of Nanotechnology, Journal of Physics Condensed Matter, Journal of Physics D: Applied Physics, etc.